

**Notice of References Cited**

Application/Control No.

09/877,923

Applicant(s)/Patent Under  
Reexamination  
DEICHSEL ET AL.

Examiner

James A. Menefee

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Art Unit

2828

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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